

# Search Notes



Application/Control No.

10/821,799

Examiner

Tien Dinh

Applicant(s)/Patent under Reexamination

FRENCH ET AL.

Art Unit

3644

## SEARCHED

Class	Subclass	Date	Examiner
116	210		
	Dig. 9		
	Dig. 8		
441	30		
	9		
446	220		
	221		
	224		
244	31	4/66	PA

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Search		3/67	PA
6			
above			

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Est Text.	4/66	B
allowance conference	3/67	PA